



Comprehensive Monitoring Technologies in Wetland and Cropland

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Message from the Guest Editors

Dear Colleagues,

The trade-offs of wetland and cropland generate new challenges for global carbon cycling and food supplying in understanding the balance of human–natural system. Innovations in remote sensing, Internet of Things (IoTs), smart equipments, and deep learning algorithms will facilitate the new potential to investigate such complex system more conveniently, accurately, and comprehensively.

Hence, this Special Issue focuses on the application of up-to-date deep learning models and the development of novel instruments to improve the monitoring of wetland, inland water, crops, and environments. Moreover, it also aims to compile the latest achievements within the topic and open up a platform where scholars can contribute their unique findings. Potential topics include, but are not limited to, those covered in the keywords.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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